## Search Notes



## Application/Control No. Applicant(s)/Patent Under Reexamination MEUNIER-BEILLARD ET AL.

| Examiner        | Art Unit |
|-----------------|----------|
| Nguyen, Khiem D | 2823     |

| SEARCHED |                              |           |          |  |
|----------|------------------------------|-----------|----------|--|
| Class    | Subclass                     | Date      | Examiner |  |
| 438      | 222, 300, 478, 479, 481, 507 | 3/22/2007 | K.N.     |  |
| 257      | E21.106                      | 3/22/2007 | K.N.     |  |
| 438      | 222, 478, 479, 481, 507      | 4/1/2008  | K.N.     |  |
| 118      | 715                          | 4/1/2008  | K.N.     |  |

| SEARCH NOTES  |           |          |  |  |
|---|-----------|----------|--|--|
| Search Notes  | Date      | Examiner |  |  |
| EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history. | 3/22/2007 | K.N.     |  |  |
| EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history. | 4/1/2008  | K.N.     |  |  |

| INTERFERENCE SEARCH |          |      |          |  |
|---------------------|----------|------|----------|--|
| Class               | Subclass | Date | Examiner |  |
|                     |          |      |          |  |

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